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|-----------------------------------|--|-------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination MURAOKA ET AL. | |
| | | Examiner | Art Unit | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------|----------------|
| | A | US-5,576,372 | 11-1996 | Kresge et al. | 524/442 |
| | B | US-2001/0009948 | 07-2001 | Hopkins et al. | 525/330.7 |
| | C | US-6,136,123 | 10-2000 | Kaido et al. | 156/123 |
| | D | US-5,700,560 | 12-1997 | Kotani et al. | 428/325 |
| | E | US-6,316,093 | 11-2001 | Kotani et al. | 428/323 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|----------------|----------------|
| * | N | WO98/56598 | 12-1998 | WO | Feeaney et al. | ----- |
| | O | EP601877A1 | 06-1994 | EP | Ou et al. | ----- |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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